US 20250266409A1

(19) **United States**

(12) **Patent Application Publication** (10) **Pub. No.: US 2025/0266409 A1**

MATSUO et al. (43) **Pub. Date: Aug. 21, 2025**

(54) **ISOLATOR**

(71) Applicants: **Kabushiki Kaisha Toshiba**, Tokyo (JP); **Toshiba Electronic Devices & Storage Corporation**, Tokyo (JP)

(72) Inventors: **Itsuki MATSUO**, Kawasaki Kanagawa (JP); **Eitaro MIYAKE**, Tachikawa Tokyo (JP); **Yuusuke IMAIZUMI**, Kawasaki Kanagawa (JP); **Jia LIU**, Yokohama Kanagawa (JP); **Yoshinari TAMURA**, Yokohama Kanagawa (JP)

(21) Appl. No.: **18/815,554**

(22) Filed: **Aug. 26, 2024**

(30) **Foreign Application Priority Data**

Feb. 15, 2024 (JP) 2024-020877

Publication Classification

(51) **Int. Cl.**

H01L 25/16	(2023.01)
H01F 27/28	(2006.01)
H01L 23/00	(2006.01)
H01L 23/31	(2006.01)
H01L 23/498	(2006.01)
H01L 23/538	(2006.01)

(52) **U.S. Cl.**

CPC ***H01L 25/16*** (2013.01); ***H01F 27/2804*** (2013.01); ***H01L 23/5385*** (2013.01); ***H10D 1/20*** (2025.01); *H01L 23/3107* (2013.01); *H01L 23/49811* (2013.01); *H01L 24/16* (2013.01); *H01L 2224/16227* (2013.01)

(57) **ABSTRACT**

According to one embodiment, an isolator device includes a rigid substrate and a flexible printed circuit board stacked on the rigid substrate in a first direction. A first coil is in the flexible printed circuit board. A second coil is also in the flexible printed circuit board, but spaced from and aligned with the first coil in the first direction. A first semiconductor chip is connected to the first coil by a first wiring. A second semiconductor chip is connected to the second coil by a second wiring.

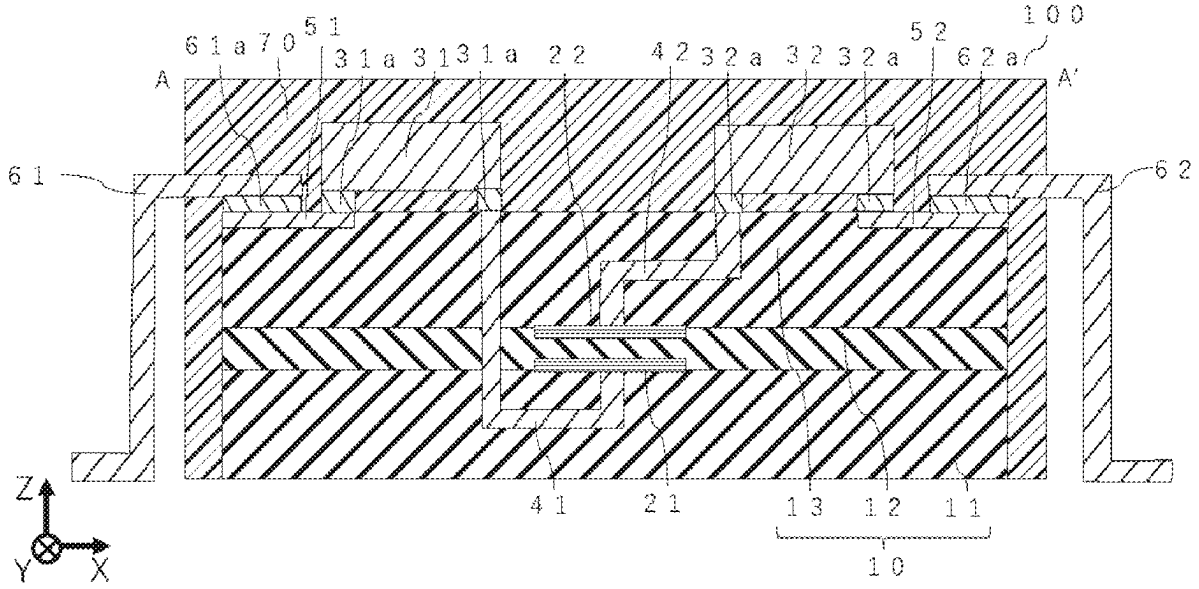


FIG. 1

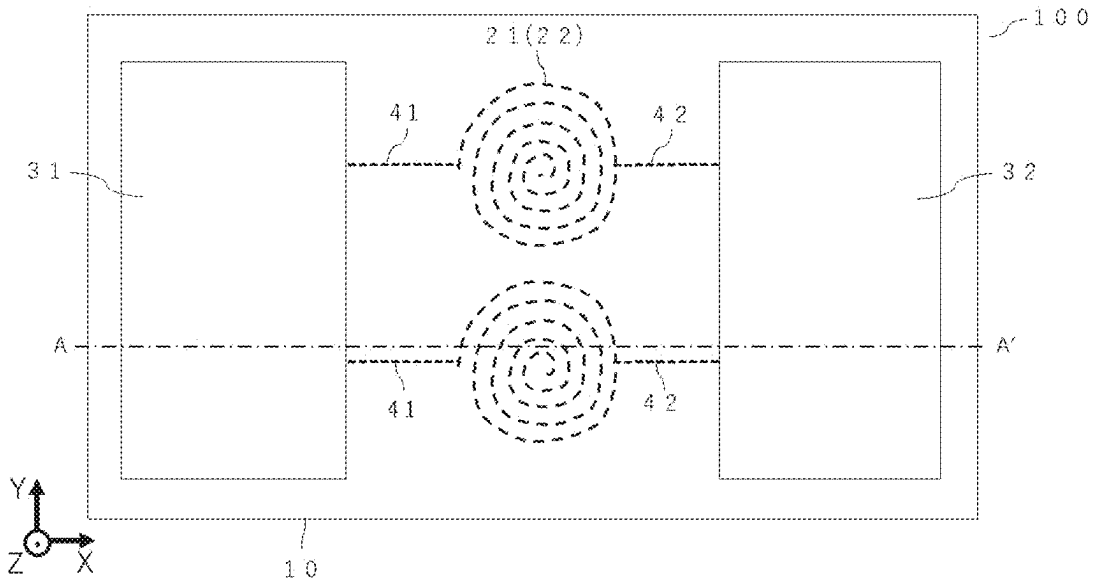

100
21(22)
41
42
31
32
A
A'
41
42
Y
Z
X
10

FIG. 2

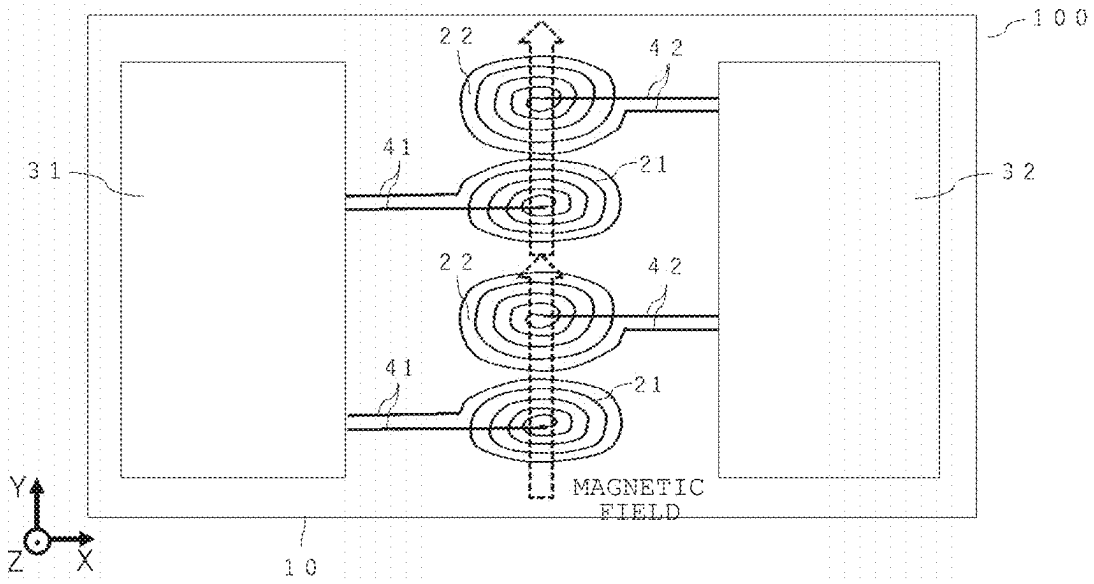

100
22
42
41
21
31
32
22
42
41
21
MAGNETIC FIELD
Y
Z
X
10

FIG. 3

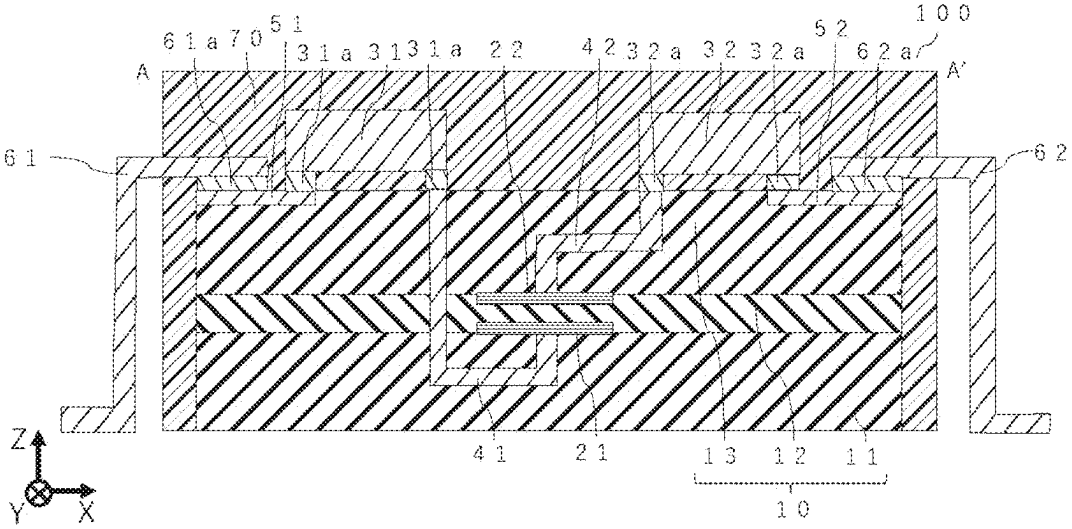

100
61a 70 51
31a 31 31a 22 42 32a 32 32a 52 62a
A
A'
61
62
41 21 13 12 11
10
Z
Y
X

FIG. 4

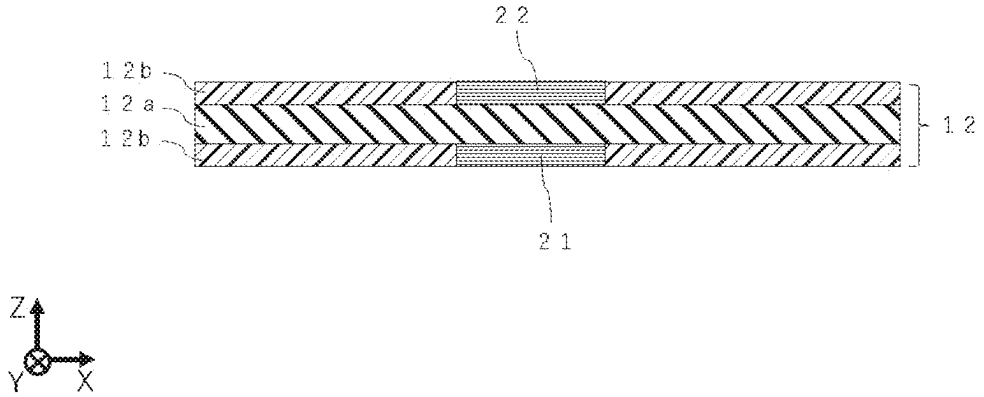

22
12b
12a
12b
12
21
Z
Y
X

FIG. 5

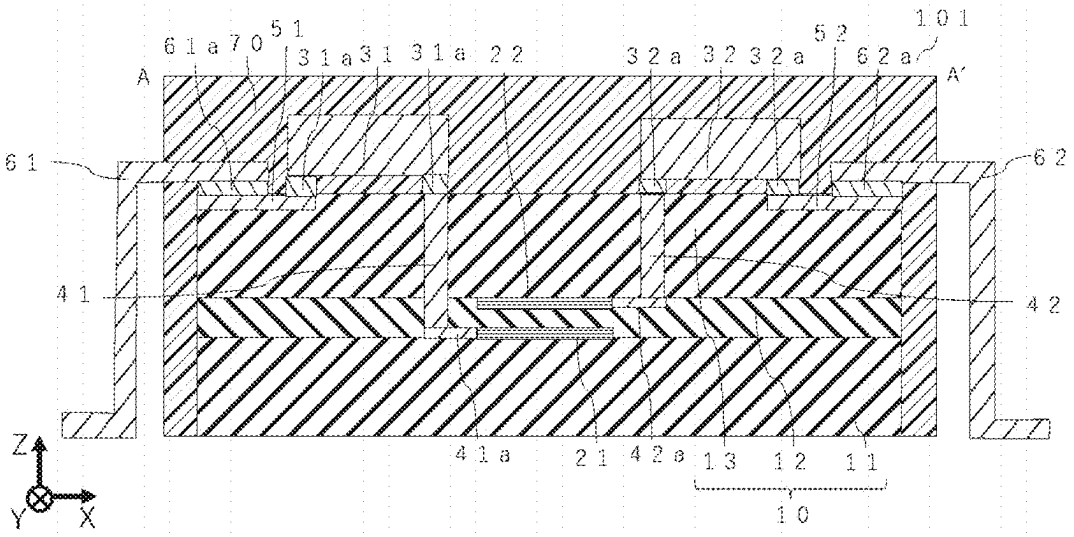

101
61a 70 51
31a 31 31a 22
32a 32 32a
52
62a
A
A'
61
62
41
42
41a
21
42a
13
12
11
10
Z
Y
X

FIG. 6

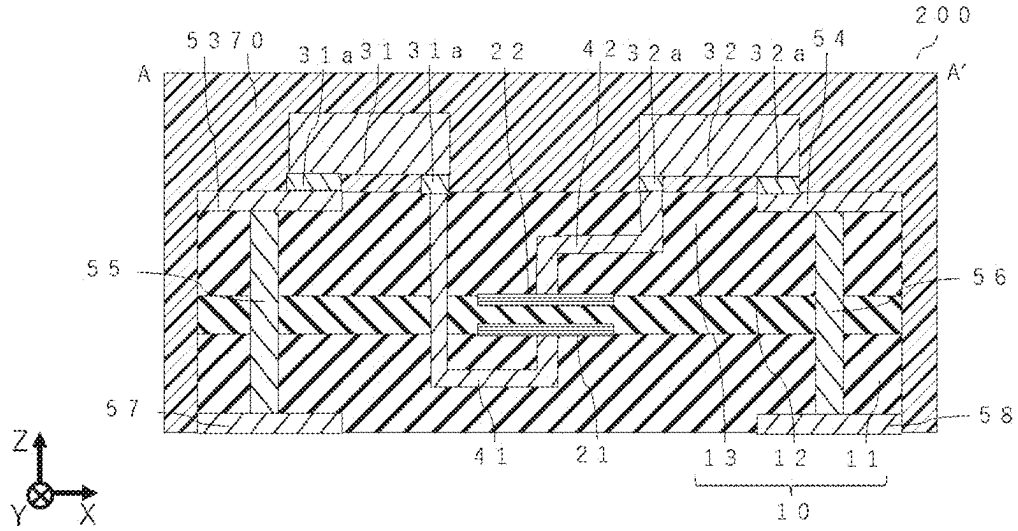

200
53 70
31a 31 31a 22
42 32a 32 32a
54
A
A'
55
56
57
58
41
21
13
12
11
10
Z
Y
X

FIG. 7

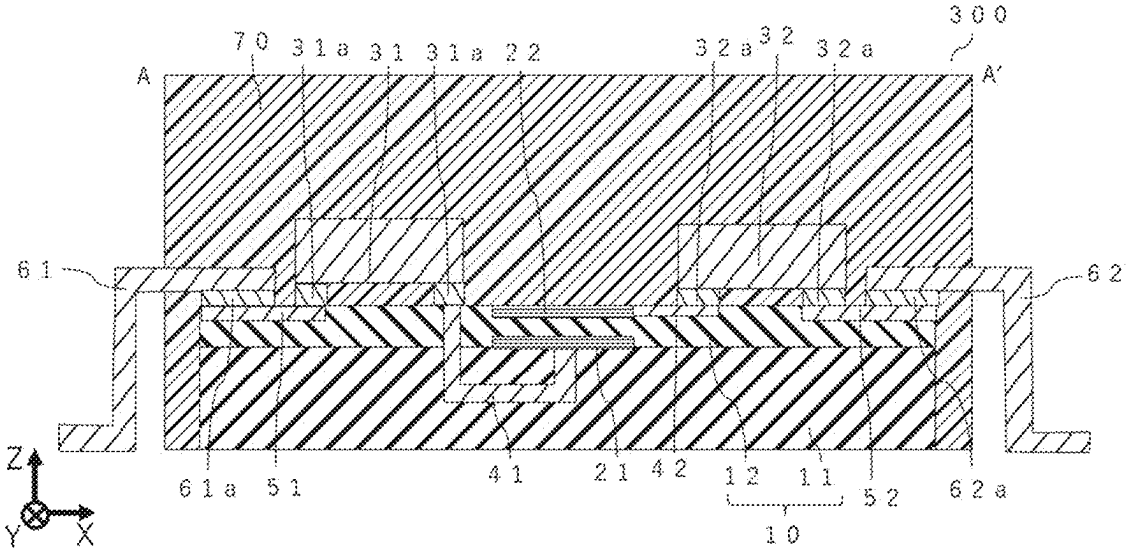

300
70
31a
31
31a
22
32a
32
32a
A
A'
61
62
61a
51
41
21
42
12
11
52
62a
10
Z
Y
X

FIG. 8

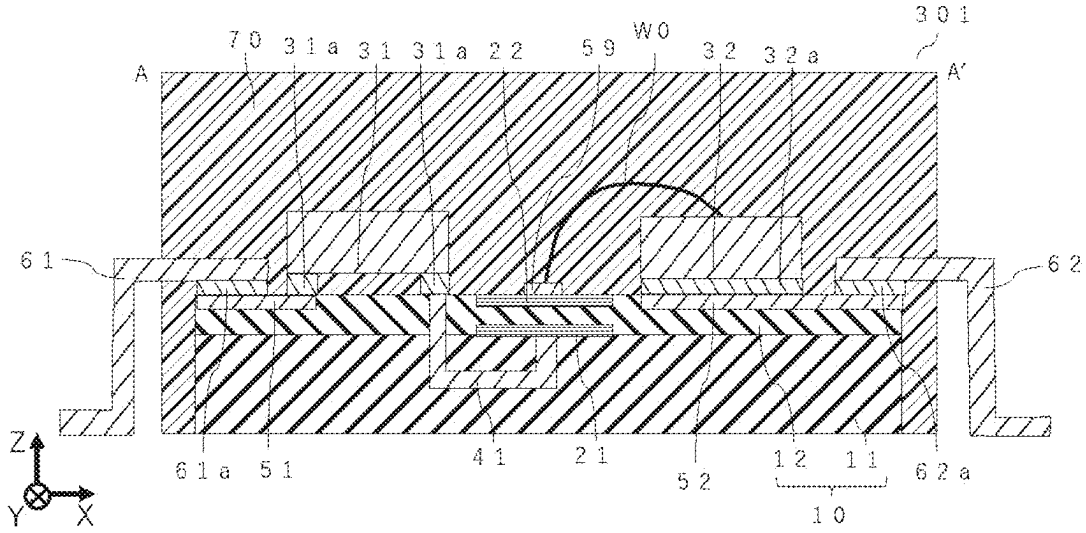
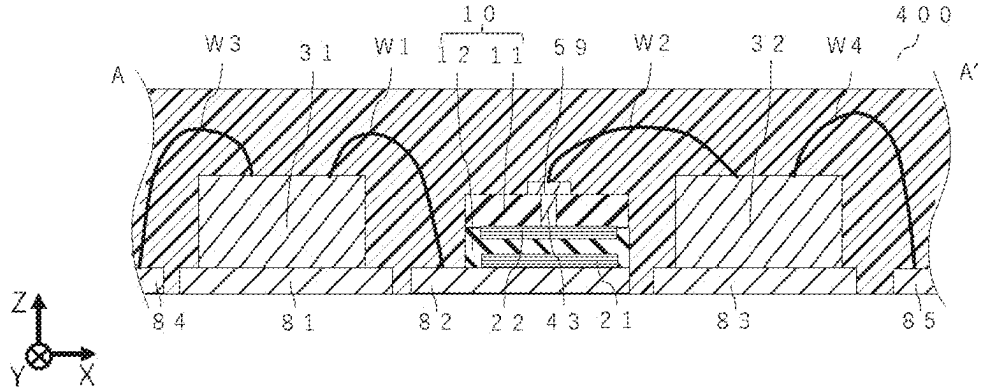

301
70
31a
31
31a
22
59
W0
32
32a
A
A'
61
62
61a
51
41
21
52
12
11
62a
10
Z
Y
X

FIG. 9



ISOLATOR

CROSS-REFERENCE TO RELATED APPLICATION

[0001] This application is based upon and claims the benefit of priority from Japanese Patent Application No. 2024-020877, filed Feb. 15, 2024, the entire contents of which incorporated herein by reference.

FIELD

[0002] Embodiments described herein relate generally to an isolator for permitting signal transmission between electrically insulated circuits, devices, or the like.

BACKGROUND

[0003] Isolators permitting the transmitting of a signal from a transmitter circuit to a receiver circuit that are electrically insulated from each other are known. Some such isolators use a light emitting element and a light receiving element but there are also isolators using wiring coils or the like.

BRIEF DESCRIPTION OF THE DRAWINGS

[0004] FIG. **1** is a schematic plan view illustrating an isolator according to a first embodiment.

[0005] FIG. **2** is a schematic view illustrating an isolator according to the first embodiment.

[0006] FIG. **3** is a cross-sectional illustrating an isolator according to a first embodiment.

[0007] FIG. **4** is a cross-sectional view illustrating an example of an internal structure of a flexible printed circuit.

[0008] FIG. **5** is a cross-sectional view illustrating an isolator according to a modification example of a first embodiment.

[0009] FIG. **6** is a cross-sectional view illustrating an isolator according to a second embodiment.

[0010] FIG. **7** is a cross-sectional view illustrating an isolator according to a third embodiment.

[0011] FIG. **8** is a cross-sectional view illustrating an isolator according to a modification example of a third embodiment.

[0012] FIG. **9** is a cross-sectional view illustrating an isolator according to a fourth embodiment.

DETAILED DESCRIPTION

[0013] Example embodiments relate to an isolator having improved reliability.

[0014] In general, according to one embodiment, an isolator device includes a first rigid substrate and a flexible printed circuit board stacked on the first rigid substrate in a first direction. A first coil is in the flexible printed circuit board. A second coil is also in the flexible printed circuit board, but spaced from and aligned with the first coil in the first direction. A first semiconductor chip is connected to the first coil by a first wiring. A second semiconductor chip is connected to the second coil by a second wiring.

[0015] According to another embodiment, an isolator device includes a first die pad, a first semiconductor chip on the first die pad, a second die pad spaced from the first die pad, and a substrate on the second die pad. The substrate includes a first rigid substrate and a flexible printed circuit board stacked on the first rigid substrate in a first direction. A first coil is in the flexible printed circuit board. A second coil is also in the flexible printed circuit board but spaced from and aligned with the first coil in the first direction. An electrode pad is on an upper surface of substrate and electrically connected to the second coil. A third die pad is spaced from the first die pad and the second die pad in a second direction intersecting the first direction. A second semiconductor chip is on the third die pad. A first wire electrically connects the first semiconductor chip to the second die pad, and a second wire electrically connects the electrode pad to the second semiconductor chip.

[0016] Hereinafter, certain example embodiments will be described with reference to the drawings.

[0017] In general, the drawings are schematic or conceptual, and as such the depicted dimensions and dimensional relationships between such things as component thicknesses, widths and the like are not necessarily those in an actual implementation but rather selected for descriptive clarity or convenience. Similarly, the depicted ratios between the sizes of different components, and the like are not necessarily the same as actual ones in an implementation of the present disclosure. In addition, even when the same component is illustrated in different drawings, its dimensions and relative sizing may vary drawing to drawing.

[0018] For example, some cross-sectional views in the present specification illustrates a stacked structure. In this case, a ratio between the thicknesses of the layers in the stacked structure is not necessarily the same as the actual one. Even when one layer is shown as thicker than another layer in the cross-sectional view, the different layers may have the same thickness or the reverse sizing relationship may be adopted. That is, any dimension such as a thickness illustrated in the drawings may be different from an actual one.

[0019] Orthogonal coordinate axes may be depicted in the drawings such that the X direction, the Y direction, and the Z direction are indicated, but such depictions are for purposes of descriptive convenience and no orientation or specific relationship between necessarily to be implied unless otherwise stated.

[0020] In addition, for convenience in description, a positive direction along the Z direction may be referred to as an "upper" or "upward" direction, and a negative direction along the Z direction may be referred to as a "lower" or "downward" direction. It should be noted that the "upper" and "lower" directions are not limited to the gravity direction or directions or orientations adopted during mounting of a semiconductor device to a substrate, board, or the like.

[0021] In the present specification and each of the drawings, those elements that are the same (or substantially so) as those already described by reference to a previous drawing are represented by the same reference symbols, and the detailed description thereof may not be repeated.

First Embodiment

[0022] FIG. **1** is a schematic plan view illustrating an isolator **100** according to the first embodiment.

[0023] The isolator **100** includes a substrate **10**, a first semiconductor chip **31**, a first wiring **41**, a first coil **21**, a second coil **22**, a second wiring **42**, and a second semiconductor chip **32**. These members are covered with a resin portion **70** (see FIG. **3**). The isolator **100** is, for example, a semiconductor package or a packaged semiconductor device.

[0024] FIG. **1** does not illustrate external connection terminals that are connected to the first semiconductor chip **31** and the second semiconductor chip **32**, but see FIG. **3** below, the isolator **100** includes lead frames **61** and **62** as terminals.

[0025] A plurality of coils is provided in substrate **10**. These coils include a first coil **21** and a second coil **22** provided in the substrate **10**. Each of the coils has, for example, a spiral shape in a plan view. The second coil **22** is disposed above (the positive direction of the Z direction) the first coil **21** and is spaced (separated) from the first coil **21** in the Z direction. In FIG. **1**, the first coil **21** and the second coil **22** overlap each other. A first coil **21** and a second coil **22** are provided to be a magnetically coupled pair.

[0026] In the example illustrated in FIG. **1**, two first coils **21** and two second coils **22** are depicted. However, the number of first coils **21** and second coils **22** are not limited to the example illustrated in FIG. **1** and any number of one or more may be provided.

[0027] The first wiring **41** electrically connects the first semiconductor chip **31** to the first coil **21**. The second wiring **42** electrically connects the second semiconductor chip **32** to the second coil **22**.

[0028] FIG. **2** is a schematic view illustrating the isolator **100** according to the first embodiment. Unlike FIG. **1**, to illustrate the presence and relationship of the first coils **21** and the second coils **22**, which overlap each other in plan view, the coils are illustrated in a tilted (non-plan view) manner to permit easier description of certain aspects.

[0029] The first wiring **41** is provided between the first semiconductor chip **31** and the first coil **21**. For example, a plurality of the first wirings **41** are formed with one first wiring **41** connected to a center portion and another first wiring **41** connected to an outer edge portion of the first coil **21**. Here, regarding the center portion and the outer edge portion of the coil, for example, a portion including one end of the coil (obtained by forming a conducting wire in a spiral shape) is defined as the center portion, and a portion including the opposite end of the coil is defined as the outer edge portion. An electrical signal can be transmitted from the first semiconductor chip **31** to the first coil **21** through the first wiring **41**. In this context, the electrical signal refers to a direction or a magnitude of a current through the first coil **21** or a change over time in the magnitude of a current in the first coil **21**.

[0030] FIG. **2** illustrates an example where the isolator **100** includes two first coils **21** and two second coils **22**. Each of the second coils **22** is disposed above a first coil **21**. The second coil **22** and the second semiconductor chip **32** are electrically connected to each other through a second wiring **42**. For example, a plurality of the second wirings **42** are formed, and one second wiring **42** is connected to a center portion of the second coil **22** and another second wiring **42** is connected to an outer edge portion of the second coil **22**.

[0031] The first coil **21** and the second coil **22** being magnetically coupled refers to a magnetic field generated by a current flowing through the first coil **21** interacts with the second coil **22** such that a current flows through the second coil **22** by electromagnetic induction. In FIG. **2**, the upward arrows indicate the magnetic field in the positive Z direction generated by the first coil **21**. Since the second coil **22** is provided above the first coil **21**, the magnetic field (arrow) illustrated in the drawing passes through the second coil **22**.

[0032] Next, an operation of the isolator **100** will be described with reference to FIG. **2**. The described example the first semiconductor chip **31** is an input side and the second semiconductor chip **32** is an output side. The isolator **100** transmits a signal from the first semiconductor chip **31** to the second semiconductor chip **32**, the first and second semiconductor chips **31** and **32** are electrically insulated from each other. First, when an input signal flows through the first semiconductor chip **31**, the input signal flows to the first coil **21** through the first wiring **41**. The current flowing through the first coil **21** generates a magnetic field as illustrated in FIG. **2**.

[0033] The second coil **22** is spaced from the first coil **21**, and an insulator material is interposed between the first coil **21** and the second coil **22** in the Z direction. That is, in general, an electrical potential of the first coil **21** and an electrical potential of the second coil **22** can be different from each other. However, the generated magnetic field can pass through the insulator material to reach the second coil **22** from the first coil **21**. Since the magnetic field passes through the second coil **22**, an induced current flows through the second coil **22**.

[0034] The current flowing through the second coil **22** then reaches the second semiconductor chip **32** through the second wiring **42**. In this way, an electrical signal is transmitted from the first semiconductor chip **31** to the second semiconductor chip **32**.

[0035] FIG. **3** is a cross-sectional view illustrating an example of a cross-sectional structure of the isolator **100**. FIG. **3** is a cross-sectional view taken along line A-A' of FIG. **1**.

[0036] As illustrated in FIG. **3**, the isolator **100** includes a substrate **10**, a first coil **21**, a second coil **22**, a first semiconductor chip **31**, a second semiconductor chip **32**, a first wiring **41**, a second wiring **42**, conductive layers **51** and **52**, lead frames **61** and **62**, and a resin portion **70**. A part of the lead frames **61** and **62** protrudes from the resin portion **70** and can be used as an external connection terminal of the isolator **100**.

[0037] The substrate **10** has a first rigid substrate **11**, a first flexible printed circuit **12** (first flexible circuit substrate), and a second rigid substrate **13** stacked one on the other. The first flexible printed circuit **12** is provided on the first rigid substrate **11**. The second rigid substrate **13** is provided on the first flexible printed circuit **12**. However, a configuration where planar members are simply stacked on each other is not a limitation and any configuration where coil members or the like can be arranged overlap each other in the Z direction can be adopted.

[0038] The first rigid substrate **11** and the second rigid substrate **13** are, for example, rigid circuit substrates comprising an epoxy resin, such as a printed circuit board or the like. The first flexible printed circuit **12** is, for example, a flexible printed circuit board (also referred to as a FPC board) that comprises a film material such as a polyimide or a liquid crystal polymer. The first flexible printed circuit **12** is formed, for example, on a film, such as a polyimide film or a polyethylene terephthalate (PET) film, as a base or substrate. Wiring and/or other circuit elements may be provided on the film. The first flexible printed circuit **12** can be any substrate material or the like having a lower stiffness than the first rigid substrate **11** and the second rigid substrate **13**.

[0039] The first flexible printed circuit **12** is provided between the first rigid substrate **11** and the second rigid substrate **13**. The first printed circuit **12** has a conductive material on both surfaces in the up-down direction (Z direction). The conductive material forms a coil on each surface. As illustrated in FIG. **3**, the first coil **21** is formed on a lower surface side of the first flexible printed circuit **12**, and the second coil **22** is formed on an upper surface side of the first flexible printed circuit **12**.

[0040] The first coil **21** and the second coil **22** are spaced from each other and face each other in the Z direction. The internal structure of the first flexible printed circuit **12** will be described below with reference to FIG. **4**.

[0041] Electrical connection between the first semiconductor chip **31** and the first wiring **41** and electrical connection between the first semiconductor chip **31** and the conductive layer **51** can be ensured by an adhesive layer **31***a*. FIG. **3** illustrates an example where each of the first semiconductor chip **31** and the second semiconductor chip include a plurality of electrodes on a lower surface. A plurality of adhesive layers **31***a* or **32***a* are respectively connected to different electrodes.

[0042] The conductive layer **51** is electrically connected to the lead frame **61** through an adhesive layer **61***a*. The adhesive layer **31***a* and **61***a* can be, for example, a solder or a silver paste.

[0043] An adhesive layer **32***a* provides electrical connection between the second semiconductor chip **32** and the second wiring **42** and electrical connection between the second semiconductor chip **32** and the conductive layer **52**. In addition, the conductive layer **52** is electrically connected to the lead frame **62** through an adhesive layer **62***a*. The adhesive layer **32***a* and **62***a* can be, for example, a solder or a silver paste.

[0044] A plurality of the first wirings **41** and a plurality of the second wirings **42** can be provided and electrically connected to the center portions and the outer edge portions of first coils **21** and second coils **22**.

[0045] In FIG. **3**, the first semiconductor chip **31** and the second semiconductor chip **32** receives an electrical signal at the lower surface (the surface facing the negative direction of the Z direction). An electrical signal is transmitted in a direction from the lead frame **61** to the first wiring **41** through the first semiconductor chip **31** or in the opposite direction thereof. For example, the first semiconductor chip **31** processes the electrical signal input via a lead frame **61**, generates electrical signals corresponding to the center portion and the outer edge portion of the first coil **21**, and outputs the generated electrical signals to the first wirings **41**. In addition, the second semiconductor chip **32** receives the electrical signal from each of the center portion and the outer edge portion of the second coil **22** through the second wiring **42**, processes the received electrical signal, and then outputs the processed electrical signal to lead frame **62**.

[0046] The first semiconductor chip **31** and the first coil **21** are electrically connected through the first wirings **41** provided in the substrate **10**. The first wiring **41** extends in the second rigid substrate **13** and the first flexible printed circuit **12** from an upper surface of the second rigid substrate **13**, and reaches the first rigid substrate **11** through a lower surface of the first flexible printed circuit **12**. The first wiring **41** may be provided between the upper surface of the second rigid substrate **13** and the lower surface of the first flexible printed circuit **12**, for example, along the Z direction. The first wiring **41** extends in an XY plane in the first rigid substrate **11** to reach a lower portion of the first coil **21**, then extends in the Z direction to be connected to the first coil **21**.

[0047] Hereinabove, the example of a basic shape of a first wiring **41** is described. However, the shape of the first wiring **41** is not limited to this example. In the first wiring **41**, as the proportion of the portion extending in the direction along the Z direction increases, the deterioration in characteristics caused by interference between a magnetic field generated from the first coil **21** and a magnetic field generated from the periphery of the first wiring **41** can be reduced, which is desirable.

[0048] The second coil **22** and the second semiconductor chip **32** are electrically connected through the second wiring **42**. The second wiring **42** extends from the second coil **22** and extends in the second rigid substrate **13** in the positive Z direction through the upper surface of the second rigid substrate **13**. Next, the second wiring **42** extends in an XY plane in the second rigid substrate **13**. Finally, the second wiring **42** extends in the second rigid substrate **13** in the Z direction and reaches the upper surface of the second rigid substrate **13**. Hereinabove, an example of a basic shape of the second wiring **42** is described. However, the shape of the second wiring **42** is not limited to this example. In the second wiring **42**, as the proportion of the portion extending in the direction along the Z direction increases, the deterioration in characteristics caused by interference between a magnetic field passing through the second coil **22** and a magnetic field generated from the periphery of the second wiring **42** can be reduced, which is desirable.

[0049] In the first wiring **41** and the second wiring **42**, the portion provided along the Z direction can be formed, for example, by drilling in the substrate **10** along the Z direction to form a via hole and then embedding (filling) a conductive material inside the via hole. In addition, in the first wiring **41** and the second wiring **42**, the portion provided in the XY plane can be obtained by allowing the first rigid substrate **11** or the second rigid substrate **13** to have a multi-layer structure and forming a wiring layer including a conductive material.

[0050] The operation of the isolator **100** will be described again with reference to FIG. **3**. A case where the lead frame **61** is an input terminal and the lead frame **62** is an output terminal will be described. The lead frame **61** provides an electrical signal to the first semiconductor chip **31** through the conductive layer **51**. The first semiconductor chip **31** executes a predetermined process on the received input signal and transmits the processed signal to the first wiring **41**. The first wiring **41** includes a portion connected to the center portion of the first coil **21** and a portion connected to the outer edge portion of the first coil **21**.

[0051] The first coil **21** receives a signal from the first semiconductor chip **31**. A current flows through the first coil **21** corresponding to the input signal received by the lead frame **61**. The current flowing through the first coil **21** generates a magnetic field in the Z direction in FIG. **3**.

[0052] When the magnetic field reaches the second coil **22** that is electrically insulated from the first coil **21** through the first flexible printed circuit **12**, a current flows through the second coil **22** by electromagnetic induction. The current flowing through the second coil **22** passes through the second wiring **42** as an electrical signal and reaches the second semiconductor chip **32**. The second semiconductor chip **32** executes a predetermined process on the received

electrical signal and outputs the processed electrical signal to the lead frame **62** through the conductive layer **52**.

[0053] Hereinafter, an example of a method of manufacturing the isolator **100** according to the first embodiment will be described. First, the first coil **21**, the second coil **22**, the first wiring **41**, the second wiring **42**, and the conductive layers **51** and **52** are formed on the substrate **10**. Next, the first semiconductor chip **31** and the second semiconductor chip **32** are mounted with the adhesive layers **31***a* and **32***a*. In addition, the lead frames **61** and **62** are provided through the adhesive layers **61***a* and **62***a*. The lead frames **61** and **62** are sealed with the resin portion **70** except for end portions functioning as input and output terminals.

[0054] Next, an example of the structure of the first flexible printed circuit **12** will be described with reference to FIG. **4**. The first flexible printed circuit **12** includes a base **12***a* (base film) and an insulator **12***b* (insulator layer). The base **12***a* is, for example, a film of insulating material such as a polyimide or a liquid crystal polymer. The insulator **12***b* can be or include, for example, a thermosetting resin such as a "prepreg." The insulator **12***b* can be on the upper and lower surfaces of the base **12***a*.

[0055] The first coil **21** is on a lower surface of the base **12***a*. The second coil **22** is on an upper surface of the base **12***a*. The insulator **12***b* is provided on both of the upper and lower surfaces of the base **12***a* to respectively cover the first coil **21** and the second coil **22**. Here, the insulator **12***b* is with a thickness greater than or equal to a thickness of the first coil **21** or the second coil **22** in the Z direction. Upper and lower surfaces of the first flexible printed circuit **12** can be kept flat by the presence of insulator **12***b*.

[0056] The substrate **10** is then formed by putting the first rigid substrate **11** and the second rigid substrate **13** on upper and lower portions of the first flexible printed circuit **12** as illustrated in FIG. **4**.

[0057] With the isolator **100** according to the first embodiment, by reducing deformation of the first flexible printed circuit **12** when the lead frames **61** and **62**, the first semiconductor chip **31**, or the second semiconductor chip **32** are mounted on the substrate **10**, deformation of the substrate **10** can be reduced, and the reliability of the isolator **100** can be improved. In this case, the deformation of the substrate **10** includes warping, bending, or displacement of the substrate **10**.

[0058] For example, when the first semiconductor chip **31** is placed, the substrate **10** locally receives a force in the Z direction. The reason for this is that the first semiconductor chip **31** positioned in the positive Z direction when seen from the substrate **10** needs to be bonded to the substrate **10** by being pressed in the negative Z direction. That is, when the first semiconductor chip **31** is mounted on the substrate **10**, stress is applied to the substrate **10**.

[0059] Here, for comparison, a case where a semiconductor chip is mounted on a substrate including only a flexible printed circuit board will be described. In a substrate including only a flexible printed circuit board, the flexible printed circuit board may be bent due to stress applied during the mounting of a semiconductor chip or the like to the flexible printed circuit. Further, a substrate including only a flexible printed circuit board is lighter than a substrate including a rigid substrate and thus displacement is more likely to occur in the lighter substrate. That is, in a substrate including only a flexible printed circuit board, unintended bending or mounting displacement may occur.

[0060] On the other hand, according to the first embodiment, the substrate **10** has a stacked structure including a flexible printed circuit board and one or more rigid substrate, the stiffness of the stacked rigid substrate(s) is higher than that of the flexible printed circuit board, and thus possibility for deformation of the flexible printed circuit board is reduced. Accordingly, deformation of the substrate **10** is reduced, and the reliability can be improved.

[0061] The substrate **10** includes the first rigid substrate **11** and the second rigid substrate **13**. For example, the first flexible printed circuit **12** (a FPC board) is interposed between these rigid substrates in the Z direction. Accordingly, to deform the substrate **10**, a higher stress is required to deform the two rigid substrates. Deformation of the substrate **10** can be further reduced.

[0062] By reducing deformation of the first flexible printed circuit **12**, improving mounting stability, and reducing breakdown and defects caused by deformation of the substrate **10**, the device (manufacturing) yield can be improved. Here, the mounting stability being high represents that, for example, when a semiconductor chip or a lead frame is mounted on to the substrate **10**, the structure of the substrate **10** can be stably maintained without being deformed by the process. According to the first embodiment, by reducing deformation of the substrate **10**, the reliability of the isolator **100** can be improved.

[0063] Electrical connection can be more reliably maintained by reducing deformation (flexibility) of the substrate **10**, and high efficiency of magnetic coupling between the coils can likewise be maintained by reducing deformation of the substrate **10**. Accordingly, signal loss in transmission can be reduced, and performance of signal transmission can be improved.

[0064] In addition, with the isolator **100** according to the first embodiment, the first wirings **41** and the second wirings **42** are implemented as the internal wiring of the substrate **10**, and separate electrical connection by a bonding wire or the like is not required. Accordingly, a wire bonding step can be skipped, the manufacturing efficiency can be improved, and the manufacturing process can be shortened.

[0065] Further, with the isolator **100**, by mounting the first coil **21** and the second coil **22** on the first flexible printed circuit **12**, the distance between the first coil **21** and the second coil **22** in the Z direction can be finely controlled to increase the magnetic coupling constant between coils. As the distance between the first coil **21** and the second coil **22** in the Z direction decreases, the magnetic field generated from the first coil **21** can reach the second coil **22** with reduced loss. That is, the magnetic coupling constant being high indicates that signal transmission loss from the first coil **21** to the second coil **22** will be small. The magnetic coupling constant can be increased by forming a coil on each of the upper and lower surfaces of a flexible printed circuit **12** having a smaller thickness as compared to a case where coils are formed on only rigid substrates.

[0066] The first wiring **41** and the second wiring **42** include a portion along the Z direction and a portion provided in the XY plane. In the first wiring **41**, focusing on the portion ranging from below the first semiconductor chip **31** to the first rigid substrate **11**, the wiring is along the Z direction. Therefore, a magnetic field generated when a current flows is in a direction orthogonal to the Z direction. A magnetic field generated along the Z direction from the first coil **21** and a magnetic field generated when a current

flows through the portion along the Z direction of the first wiring **41** are orthogonal to each other. Since the magnetic fields are orthogonal to each other, interference of magnetic fields can be reduced, and deterioration in characteristics relating to noise can be reduced.

[0067] The portion of the first wiring **41** or the second wiring **42** provided parallel to the XY plane in the first rigid substrate **11** and the second rigid substrate **13** are spaced from the first coil **21** and the second coil **22** in the Z direction. Since the portions are spaced from the first coil **21** and the second coil **22** in this manner, interference of magnetic fields can be reduced.

[0068] Interference of magnetic fields between the coils (the first coil **21** and the second coil **22**) and the wirings (the first wiring **41** and the second wiring **42**) varies depending on a layout of the wirings and the like. Therefore, when a positional relationship between the coils and the wirings changes depending on deformation of the substrate **10**, interference of magnetic fields may be promoted. According to the present embodiment, by reducing deformation of the substrate **10**, deterioration in characteristics caused by interference can be reduced.

First Modification Example of First Embodiment

[0069] FIG. **5** illustrates a cross-sectional structure of an isolator **101** according to a first modification example of the first embodiment.

[0070] The isolator **101** is different from the isolator **100** in the structure for connecting the first semiconductor chip **31** and the first coil **21** and/or the structure for connecting the second semiconductor chip **32** and the second coil **22**.

[0071] The first wiring **41** includes a first portion **41***a* formed on the first flexible printed circuit **12**. The first portion **41***a* extends along the lower surface of the first flexible printed circuit **12** and is connected to the first coil **21**.

[0072] The second wiring **42** includes a first portion **42***a* formed on the first flexible printed circuit **12**. The first portion **42***a* extends along the upper surface of the first flexible printed circuit **12** and is connected to the second coil **22**.

[0073] The first portion **41***a* of the first wiring **41** and the first portion **42***a* of the second wiring **42** are provided, for example, in the insulator **12***b* (illustrated in FIG. **4**) of the first flexible printed circuit **12**. For example, the first portion **41***a* and the first portion **42***a* may be formed by adding a step of forming a layer including a conductive material to a step of forming the insulator **12***b*.

[0074] A plurality of the first portions **41***a* can be provided and can be connected to the center portions and the outer edge portions of the various first coils **21**, respectively. A plurality of the first portions **42***a* can be provided and can be connected to the center portions and the outer edge portions of the second coils **22**, respectively.

[0075] With the isolator **101**, by providing the first portions **41***a* and **42***a* on the first flexible printed circuit **12**, the wiring length for electrical connection between the semiconductor chip (**31** or **32**) and the coil (**21** or **22**) can be reduced.

[0076] The electrical connection between semiconductor chip and coil can be established through a shorter total wiring length. Therefore, a magnetic field generated when a current flows through the connecting wiring can be reduced. Accordingly, deterioration in characteristics caused by interference of magnetic fields can be reduced. Loss of signal in transmission between the first coil **21** and the second coil **22** can be further reduced.

Second Embodiment

[0077] FIG. **6** illustrates a cross-sectional structure of an isolator **200** according to a second embodiment.

[0078] The isolator **200** according to the second embodiment includes back electrodes **57** and **58**. The back electrode **57** is electrically connected to the first semiconductor chip **31** (the adhesive layer **31***a* provided below the first semiconductor chip **31**) through a conductive layer **53** provided below the first semiconductor chip **31** and a through-conductive region **55** provided between the conductive layer **53** and the back electrode **57**. The back electrode **57** is, for example, an input terminal.

[0079] The back electrode **58** is electrically connected to the second semiconductor chip **32** (the adhesive layer **32***a* provided below the second semiconductor chip **32**) through a conductive layer **54** provided below the second semiconductor chip **32** and a through-conductive region **56** provided between the conductive layer **54** and the back electrode **58**. The back electrode **58** is, for example, an output terminal.

[0080] The conductive layers **53** and **54** are formed on the second rigid substrate **13**. The back electrodes **57** and **58** are formed on the first rigid substrate **11**. The conductive layers **53** and **54** and the back electrodes **57** and **58** can be obtained, for example, by forming a layer including a conductive material on a rigid substrate having a multi-layer structure.

[0081] The through-conductive regions **55** and **56** penetrate the first rigid substrate **11**, the first flexible printed circuit **12**, and the second rigid substrate **13** in the Z direction. The through-conductive regions **55** and **56** are formed, for example, by drilling in the Z direction to form a via hole and then embedding a conductive material in the via hole.

[0082] With the isolator **200** to the second embodiment, an input terminal and an output terminal can be formed by having exposed electrodes on the back surface of the isolator **200**. A package that is applicable to a configuration of mounting different from that in the isolator **100** according to the first embodiment can be provided. Not only the isolator **100** or the isolator **200** but also various structures of terminals of packages can be adopted.

Third Embodiment

[0083] FIG. **7** illustrates a cross-sectional structure of an isolator **300** according to a third embodiment.

[0084] The substrate **10** in the isolator **300** has only a two-layer structure including a first rigid substrate **11** and a first flexible printed circuit **12**. The first rigid substrate **11**, and the first flexible printed circuit **12**. The first flexible printed circuit **12** is provided on the first rigid substrate **11**.

[0085] The conductive layers **51** and **52** are formed on the upper surface of the first flexible printed circuit **12**. The conductive layers **51** and **52** are formed, for example, in the insulator **12***b* (illustrated in FIG. **4**) of the first flexible printed circuit **12**.

[0086] The first semiconductor chip **31** and the second semiconductor chip **32** are provided on the first flexible printed circuit **12** through the adhesive layers **31***a* and **32***a*. In addition, the lead frames **61** and **62** are provided on the conductive layers **51** and **52** through the adhesive layers **61***a*

and **62***a*. The lead frame **61** is, for example, an input terminal, and the lead frame **62** is, for example, an output terminal.

[0087] The first wiring **41** extends in the first flexible printed circuit **12** and the first rigid substrate **11** and connects the adhesive layer **31***a* below the first semiconductor chip **31** to the first coil **21**. The shape of the first wiring **41** is not limited to the shape illustrated in FIG. **7** and, in other examples, the first wiring **41** may be formed of only in the first flexible printed circuit **12** rather than with a portion in the first rigid substrate **11**.

[0088] The second wiring **42** connected to the second coil **22** is formed in the insulator **12***b* (illustrated in FIG. **4**) of the first flexible printed circuit **12**. The second wiring **42** extends along the upper surface of the first flexible printed circuit **12** and is connected to the second coil **22**. The plurality of second wirings **42** connected to the center portions and the outer edge portions of the second coils **22**, respectively, are connected to the second semiconductor chip **32** through the adhesive layer **32***a*.

[0089] With the isolator **300** according to the third embodiment, the substrate **10** has a two-layer structure, and thus the package can be made smaller than with a three-layer structure. The substrate **10** includes the first rigid substrate **11** and the first flexible printed circuit **12**. As compared to the isolator **100** according to the first embodiment, the thickness of the substrate **10** can be reduced by the thickness corresponding to the second rigid substrate **13**. Accordingly, the package can be made smaller.

[0090] The substrate **10** still includes first rigid substrate **11**, and thus can still reduce deformation of the first flexible printed circuit **12**. The reliability of the isolator **300** can be improved as compared to only a design with only a FCP board.

[0091] In FIG. **7**, electrical connection between the second coil **22** and the second semiconductor chip **32** does not require a wire bonding step and this can reduce manufacturing steps.

[0092] In addition, the wiring length of the first wiring **41** in the third embodiment can be reduced as compared to the first embodiment. Therefore, deterioration in characteristics relating to signal transmission caused by interference can be reduced. The second wiring **42** extending in the Z direction (illustrated in FIG. **3**) is not required, and interference of magnetic fields can be further reduced.

First Modification Example of Third Embodiment

[0093] An isolator **301** according to a first modification example of the third embodiment will be described with reference to FIG. **8**.

[0094] FIG. **8** illustrates an example where electrodes are provided such that the second semiconductor chip **32** transmits an electrical signal in a direction from the upper surface to the lower surface.

[0095] The first coil **21** is formed on the lower surface of the first flexible printed circuit **12**, and the second coil **22** is formed on the upper surface. An electrode pad **59** electrically connected to the second coil **22** is provided on the second coil **22**. A wire W**0** connects the electrode pad **59** to an upper surface of the second semiconductor chip **32**. The wire W**0** is connected to the electrode pad **59** by wire bonding.

[0096] A plurality of the electrode pads **59** are provided, for example, arrayed in the XY plane and are connected to the second coils **22**, and a plurality of the wires W**0** are also correspondingly provided.

[0097] With the isolator **301** according to the first modification example of the third embodiment, when electrical connection between the upper surface of the semiconductor chip (for example, the second semiconductor chip **32**) and the coil (for example, the second coil **22**) is established by wire bonding, deformation of the substrate **10** can be reduced. The substrate **10** includes the first rigid substrate **11** below the first flexible printed circuit **12**, and thus can have reduced deformation of the first flexible printed circuit **12**. The reliability of the isolator **301** can be improved.

Fourth Embodiment

[0098] FIG. **9** illustrates a cross-sectional structure of an isolator **400** according to a fourth embodiment.

[0099] The isolator **400** includes a first semiconductor chip on a first die pad **81**. The substrate **10** is provided on a second die pad **82**. The second semiconductor chip **32** is provided on a third die pad **83**. The first die pad **81**, the second die pad **82**, and the third die pad **83** are spaced from each other in the X direction.

[0100] The first semiconductor chip **31** includes electrodes on its upper surface and, while the first semiconductor chip **31** is in contact with the first die pad **81**, it is electrically insulated from the first die pad **81**. The second semiconductor chip **32** includes electrodes on its upper surface and, while the second semiconductor chip is in contact with the third die pad **83**, it is electrically insulated from the third die pad **83**.

[0101] A wiring including a coil is provided in the substrate **10** and a part of this wiring is electrically connected to the second die pad **82**.

[0102] The first semiconductor chip **31** and the second die pad **82** are electrically connected through a wire W**1**. The wire W**1** is in contact with an upper surface of the first semiconductor chip **31** and an upper surface of the second die pad **82**. The substrate **10** and the second semiconductor chip **32** are electrically connected through a wire W**2**.

[0103] The substrate **10** has a two-layer structure with a first rigid substrate **11** and a first flexible printed circuit **12**. The first rigid substrate **11**. The first flexible printed circuit **12**. In the example illustrated in FIG. **9**, the first rigid substrate **11** is provided above the first flexible printed circuit **12**.

[0104] The first coil **21** and the second coil **22** are provided in the first flexible printed circuit **12**. The internal structure of the first flexible printed circuit **12** can be the same as illustrated in FIG. **4**. The first coil **21** is provided on the lower surface of the first flexible printed circuit **12**, and the second coil **22** is provided on the upper surface of the first flexible printed circuit **12**. The first coil **21** is electrically connected to the second die pad **82**. The second coil **22** is electrically insulated from the first coil **21**.

[0105] A third wiring **43** connected to the second coil **22** penetrates into the first rigid substrate **11** in the Z direction. The third wiring **43** is connected to the electrode pad **59** provided on the upper surface of the first rigid substrate **11**. The wire W**2** is connected to the electrode pad **59**.

[0106] The isolator **400** includes external terminals **84** and **85**. The external terminals **84** and **85** are spaced from the first die pad **81**, the second die pad **82**, and the third die pad

83. The external terminal **84** is, for example, an input terminal. The external terminal **85** is, for example, an output terminal.

[0107] The external terminal **84** and the first semiconductor chip **31** are electrically connected through a wire W**3**. The external terminal **85** and the second semiconductor chip **32** are electrically connected through a wire W**4**. That is, the first semiconductor chip **31** includes a plurality of electrodes on the upper surface, one of the electrodes is connected to the second die pad **82** through a wire W**1**, and another electrode is connected to the external terminal **84** through a wire W**3**. That is, the second semiconductor chip **32** includes a plurality of electrodes on the upper surface, one of the electrodes is connected to the electrode pad **59** through a wire W**2**, and another electrode is connected to the external terminal **85** through a wire W**4**.

[0108] Next, an operation of the isolator **400** will be described. An example where the external terminal **84** is an input terminal and the external terminal **85** is an output terminal will be described.

[0109] An electrical signal input to the external terminal **84** reaches the first semiconductor chip **31** through the wire W**3**. The first semiconductor chip **31** executes a predetermined process on the received electrical signal and outputs the processed electrical signal to the wire W**1**. The signal output from the first semiconductor chip **31** reaches the first coil **21** from the wire W**1** through the second die pad **82**.

[0110] The first coil **21** generates a magnetic field based on the received electrical signal. For example, in FIG. **9**, a magnetic field in the Z direction is generated. The magnetic field in the Z direction pass through the second coil **22** spaced from the first coil **21** in the Z direction. A current flows through the second coil **22** by electromagnetic induction. A signal is transmitted between the first coil **21** and the second coil **22** through the magnetic field.

[0111] The signal transmitted to the second coil **22** flows to the wire W**2** through the third wiring **43** and the electrode pad **59**. The signal is transmitted to the second semiconductor chip **32** through the wire W**2**. The second semiconductor chip **32** executes a predetermined process on the signal and outputs the processed signal to the wire W**4**. The signal transmitted to the external terminal **85** from the wire W**4** is an output signal.

[0112] With the isolator **400** according fourth embodiment, while thinning the substrate **10** to make the package smaller, deformation of the first flexible printed circuit **12** can be reduced, and the reliability can be improved.

[0113] The substrate **10** has a two-layer structure where the first rigid substrate **11** and the first flexible printed circuit **12** are stacked. As compared to the isolator **100** according to the first embodiment, the thickness of the substrate **10** can be reduced. By reducing the thickness of the substrate **10**, the package can be made smaller.

[0114] The first rigid substrate **11** is rigid, so when the wire W**2** or the like is formed by wire bonding, deformation of the first flexible printed circuit **12** can be reduced. The reliability of the isolator **400** can be improved.

[0115] In some examples, the first rigid substrate **11** may have a smaller planar area than the first flexible printed circuit **12**. The electrode pad **59** can be provided on the first rigid substrate **11**. Stress is applied to the substrate **10** in the wire bonding step of connecting the wire W**2** to the electrode pad **59**. However, since the first rigid substrate **11** can be positioned at least below the electrode pad **59**, stress applied during mounting of the wire W**2** can be dispersed to the first rigid substrate **11**. By reducing the amount of a material forming the first rigid substrate **11**, the manufacturing cost can be reduced.

[0116] In at least one of the embodiments described above, the substrate **10** has a structure of at least two layers including a rigid substrate layer and a flexible printed circuit board layer, and deformation of a first flexible printed circuit **12** where the first coil **21** and the second coil are disposed can be reduced. By improving the mounting stability and reducing breakdown and defects, the reliability of an isolator device can be improved. In addition, by forming a coil on both the upper and lower surfaces of the first flexible printed circuit **12**, magnetic coupling coefficient can be increased by reducing the distance between coils, and performance relating to signal transmission can be improved. Further, regarding the structure for connecting the first semiconductor chip **31** and the first coil **21** or the second semiconductor chip and the second coil **22**, deterioration in characteristics relating to signal transmission caused by interference from connecting wiring can be reduced.

[0117] Hereinabove, an isolator using a coil has been described. However, the embodiments are also applicable to an isolator using a capacitor.

[0118] In addition, the elements in the various above-described embodiments may be combined with one another as long as these combinations are technically possible, and such combinations are to be considered as within the scope of the present disclosure. In addition, those skilled in the art can conceive various changes and modifications from the concepts of the various example embodiments, and it is understood that these changes and modifications are also within the scope of the present disclosure.

[0119] While certain embodiments have been described, these embodiments have been presented by way of example only, and are not intended to limit the scope of the disclosure. Indeed, the novel embodiments described herein may be embodied in a variety of other forms; furthermore, various omissions, substitutions and changes in the form of the embodiments described herein may be made without departing from the spirit of the disclosure. The accompanying claims and their equivalents are intended to cover such forms or modifications as would fall within the scope and spirit of the disclosure.

What is claimed is:

1. An isolator device, comprising:

a first rigid substrate;

a flexible printed circuit board stacked on the first rigid substrate in a first direction;

a first coil in the flexible printed circuit board;

a second coil in the flexible printed circuit board, the second coil spaced from and aligned with the first coil in the first direction;

a first semiconductor chip connected to the first coil by a first wiring; and

a second semiconductor chip connected to the second coil by a second wiring.

2. The isolator device according to claim **1**, wherein the flexible printed circuit board is between the first rigid substrate and the first and second semiconductor chips in the first direction.

3. The isolator device according to claim **2**, wherein the first wiring extends through the flexible printed circuit board in the first direction.

4. The isolator device according to claim 2, further comprising:
a second rigid substrate stacked on the flexible printed circuit board, wherein
the flexible printed circuit board is between the first rigid substrate and the second rigid substrate in the first direction.
5. The isolator device according to claim 4, wherein the first wiring extends through the second rigid substrate in the first direction.
6. The isolator device according to claim 5, wherein the second wiring extends through the second rigid substrate in the first direction.
7. The isolator device according to claim 6, wherein the first wiring extends in the first direction through a portion of the first rigid substrate and in a second direction parallel to an upper surface of the first rigid substrate.
8. The isolator device according to claim 5, wherein a first portion of the first wiring extends in a second direction parallel to a surface of the flexible printed circuit board along the surface of the flexible printed circuit board and connects to the first coil.
9. The isolator device according to claim 1, further comprising:
a resin covering the first semiconductor chip and the second semiconductor chip;
a first lead frame including a portion extending out of the resin, the first lead frame electrically connected to the first semiconductor chip; and
a second lead frame including a portion extending out of the resin, the second lead frame electrically connected to the second semiconductor chip.
10. The isolator device according to claim 1, further comprising:
a resin covering the first semiconductor chip and the second semiconductor chip;
a first back electrode on a backside surface of the first rigid substrate;
a second back electrode on the backside surface of the first rigid substrate;
a first through-conductive region extending in the first direction through the flexible printed circuit board and the first rigid substrate and electrically connected to the first back electrode;
a second through-conductive region extending in the first direction through the flexible printed circuit board and the first rigid substrate and electrically connected to the second back electrode;
a first conductive layer electrically connecting the first semiconductor chip to the first-through conductive region; and
a second conductive layer electrically connecting the second semiconductor chip to the second-through conductive region.
11. The isolator device according to claim 1, wherein the flexible printed circuit board comprises:
a base film,
a first insulator layer on a first surface of the base film, and
a second insulator layer on a second surface of the base film.
12. The isolator device according to claim 11, wherein
the first coil is on the first surface of the base film,
the second coil is on the second surface of the base film,
the thickness of the first insulator layer on the first surface is greater than or equal to the thickness of the first coil in the first direction, and
the thickness of the second insulator layer on the second surface is greater than or equal to the thickness of the second coil in the first direction.
13. The isolator device according to claim 11, wherein
the base film is polyimide,
the first insulator layer is a thermosetting resin, and
the second insulator layer is a thermosetting resin.
14. The isolator device according to claim 1, further comprising:
a first die pad;
a second die pad spaced from the first die pad in a second direction intersecting the first direction; and
a third die pad between the first and second die pads in the second direction, wherein
the first semiconductor chip is on the first die pad,
the second semiconductor chip is on the second die pad, and
the first rigid substrate and the flexible printed circuit board are on the third die pad.
15. An isolator device, comprising:
a first die pad;
a first semiconductor chip on the first die pad;
a second die pad spaced from the first die pad;
a substrate on the second die pad and including a first rigid substrate and a flexible printed circuit board stacked on the first rigid substrate in a first direction;
a first coil in the flexible printed circuit board;
a second coil in the flexible printed circuit board, the second coil spaced from and aligned with the first coil in the first direction;
an electrode pad on an upper surface of substrate and electrically connected to the second coil;
a third die pad spaced from the first die pad and the second die pad in a second direction intersecting the first direction;
a second semiconductor chip on the third die pad;
a first wire electrically connecting the first semiconductor chip to the second die pad; and
a second wire electrically connecting the electrode pad to the second semiconductor chip.
16. The isolator device according to claim 15, wherein
the flexible printed circuit board comprises:
a base film,
a first insulator layer on a first surface of the base film, and
a second insulator layer on a second surface of the base film,
the first coil is on the first surface of the base film, and
the second coil is on the second surface of the base film.
17. The isolator device according to claim 16, wherein
the base film is polyimide,
the first insulator layer is a thermosetting resin, and
the second insulator layer is a thermosetting resin.
18. An isolator device, comprising:
a first rigid substrate;
a flexible circuit substrate stacked on the first rigid substrate in a first direction;
a second rigid substrate stacked on the flexible circuit substrate;
a first coil in the flexible circuit substrate;

a second coil in the flexible circuit substrate, the second coil spaced from and aligned with the first coil in the first direction;

a first semiconductor chip mounted on the second rigid substrate and connected to the first coil by a first wiring with at least a portion of the first wiring extending in the second rigid substrate; and

a second semiconductor chip mounted on the second rigid substrate and connected to the second coil by a second wiring with at least a portion of the second wiring extending in the second rigid substrate.

19. The isolator device according to claim **18**, further comprising:

a resin covering the first and second semiconductor chips and contacting the second rigid substrate.

20. The isolator device according to claim **18**, wherein the flexible circuit substrate comprises:

a base film,

a first insulator layer on a first surface of the base film, and

a second insulator layer on a second surface of the base film,

the first coil is on the first surface of the base film, and

the second coil is on the second surface of the base film.

* * * * *